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THIS SPEC IS OBSOLETE

Spec No: 38-05256

Spec Title: CY7C1061AV33, 16-MBIT (1M X 16) STATIC RAM

Replaced by: None



CY7C1061AV33

16-Mbit (1M × 16) Static RAM

Features

- High speed □ t_{AA} = 10 ns
- Low active power □ 990 mW (max)
- Operating voltages of 3.3 ± 0.3 V
- 2.0 V data retention
- Automatic power down when deselected
- TTL compatible inputs and outputs
- Easy memory expansion with CE₁ and CE₂ features
- Available in Pb-free and non Pb-free 54-pin TSOP II package and non Pb-free 60-ball fine-pitch ball grid array (FBGA) package

Functional Description

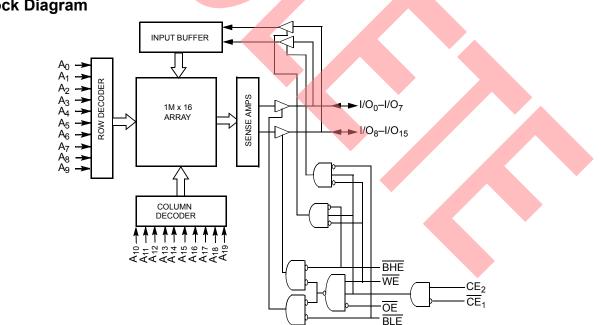
The CY7C1061AV33 is a high performance CMOS Static RAM organized as 1,048,576 words by 16 bits.

To write to the device, enable the chip (\overline{CE}_1 LOW and CE_2 HIGH) while forcing the Write Enable (WE) input LOW. If Byte Low Enable (BLE) is LOW, then data from I/O pins (I/O₀ through I/O₇), is written into the location specified on the address pins (A₀ through A₁₉). If Byte High Enable (BHE) is LOW, then data from I/O pins (I/O₈ through I/O₁₅) is written into the location specified on the address pins (A₀ through A₁₉).

To read from the device, enable the chip by taking \overline{CE}_1 LOW and CE_2 HIGH while forcing the Output Enable (\underline{OE}) LOW and the Write Enable (WE) HIGH. If Byte Low Enable (BLE) is LOW, then data from the memory location specified by the address pins will appear on I/O₀ to I/O₇. If Byte High Enable (BHE) is LOW, then data from memory will appear on I/O₈ to I/O₁₅. See Truth Table on page 11 for a complete description of Read and Write modes.

The input/output pins (I/O₀ through I/O₁₅) are placed in a high-impedance state when the device is deselected ($\underline{CE_1}$ HIGH/CE₂ LOW), the outputs are disabled (OE HIGH), the BHE and BLE are disabled (BHE, BLE HIGH), or a Write operation is in progress (CE₁ LOW, CE₂ HIGH, and WE LOW).

For a complete list of related documentation, click here.



Logic Block Diagram

Cypress Semiconductor Corporation Document Number: 38-05256 Rev. *N 198 Champion Court • San Jose, CA 95134-1709 • 408-943-2600 Revised May 16, 2017



CY7C1061AV33

Contents

Selection Guide	
Pin Configurations	
Maximum Ratings	
Operating Range	5
DC Electrical Characteristics	
Capacitance	6
AC Test Loads and Waveforms .	
Data Retention Waveform	
AC Switching Characteristics	
Switching Waveforms	
Truth Table	
Ordering Information	
Ordering Code Definitions	
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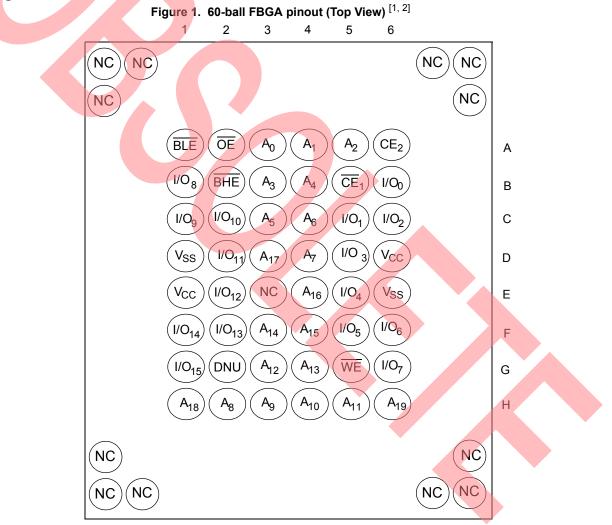
Package Diagrams Acronyms	
Document Conventions	
Units of Measure	15
Document History Page	16
Sales, Solutions, and Legal Information	17
Worldwide Sales and Design Support	17
Products	17
PSoC® Solutions	17
Cypress Developer Community	17
Technical Support	17



Selection Guide

Description	-10	Unit	
Maximum Access Time		10	ns
Maximum Operating Current	Commercial	275	mA
	Industrial	275	
Maximum CMOS Standby Current	Commercial / Industrial	50	mA

Pin Configurations



Notes

- 1. NC pins are not connected on the die.
- 2. DNU (Do Not Use) pins have to be left floating or tied to VSS to ensure proper operation.





Pin Configurations (continued)

Figure 2. 54-pin TSOP II pinout (Top View) $^{[3, 4]}$

A10 18 37 A11 A10 19 36 A12 A11 21 34 A14 I/Q 22 33 I/Q VC 24 31 I/Q VQ 25 30 I/Q VS 26 29 VCC I/Q 27 28 I/Q	$\begin{array}{c ccccccccccccccccccccccccccccccccccc$
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 Notes

 3. NC pins are not connected on the die.

 4. DNU (Do Not Use) pins have to be left floating or tied to VSS to ensure proper operation.



Maximum Ratings

Exceeding maximum ratings may shorten the useful life of the device. These user guidelines are not tested.

Storage Temperature	–65 °C to +150 °C
Ambient Temperature with Power Applied	–55 °C to +125 °C
Supply Voltage on V _{CC} to Relative GND ^[5]	-0.5 V to +4.6 V
DC Voltage Applied to Outputs in High Z State ^[5]	–0.5 V to V _{CC} + 0.5 V

DC Input Voltage [5]	–0.5 V to V _{CC} + 0.5 V
Current into Outputs	(LOW)

Operating Range

Range	Ambient Temperature	V _{CC}
Commercial	0 °C to +70 °C	$3.3~V\pm0.3~V$
Industrial	–40 °C to +85 °C	

DC Electrical Characteristics

Over the Operating Range

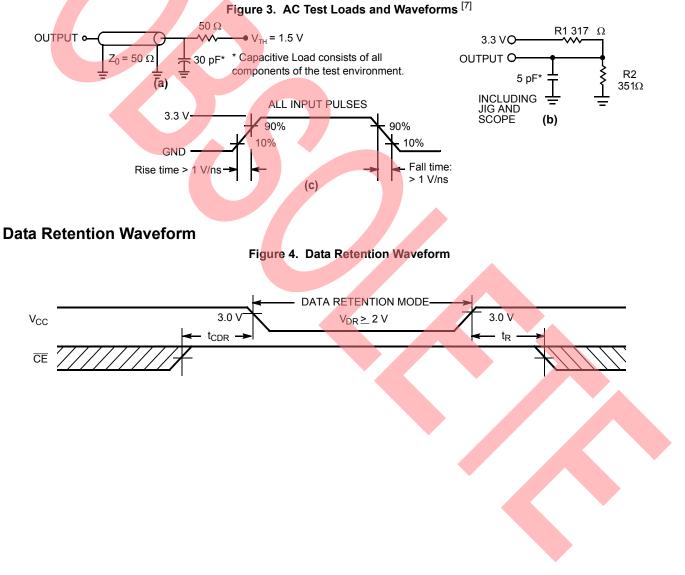
Deremeter	Description	Test Canditions	-1	Unit		
Parameter	Description	Test Conditions	Min	Max	Unit	
V _{OH}	Output HIGH Voltage	$I_{OH} = -4.0 \text{ mA}$		2.4	_	V
V _{OL}	Output LOW Voltage	I _{OL} = 8.0 mA		_	0.4	V
V _{IH}	Input HIGH Voltage			2.0	V _{CC} + 0.3	V
V _{IL}	Input LOW Voltage ^[5]			-0.3	0.8	V
I _{IX}	Input Leakage Current	$GND \le V_1 \le V_{CC}$		–1	+1	μA
I _{OZ}	Output Leakage Current	$GND \leq V_O \leq V_{CC}$, Output Disablec	1	-1	+1	μΑ
I _{CC}	V _{CC} Operating Supply Current	$V_{CC} = \max, f = f_{max} = 1/t_{RC}$	Commercial	_	275	mA
			Industrial	_	275	mA
I _{SB1}	Automatic CE Power-down	$CE_2 \leq V_{IL}$, Max V_{CC} , $\overline{CE} \geq V_{IH}$,		-	70	mA
	Current – TTL Inputs	$V_{IN} \ge V_{IH} \text{ or } V_{IN} \le V_{IL}, f = f_{max}$				ĺ
I _{SB2}	Automatic CE Power-down	CE ₂ ≤ 0.3 V, Max V _{CC} ,	Commercial	-	50	mA
	Current – CMOS Inputs	$\overline{CE} \ge V_{CC} - 0.3 \text{ V},$	/ Industrial			
		$V_{IN} \ge V_{CC} - 0.3 \text{ V, or } V_{IN} \le 0.3 \text{ V,}$				
		f = 0				



Capacitance

Parameter [6]	Description	Test Conditions	TSOP II	FBGA	Unit
C _{IN}	Input capacitance	T _A = 25 °C, f = 1 MHz, V _{CC} = 3.3 V	6	8	pF
C _{OUT}	I/O capacitance		8	10	pF

AC Test Loads and Waveforms



Notes

- 6. Tested initially and after any design or process changes that may affect these parameters.
- 7. Valid SRAM operation does not occur until the power supplies have reached the minimum operating V_{DD} (3.0 V). As soon as 1 ms (T_{power}) after reaching the minimum operating V_{DD} , normal SRAM operation can begin including reduction in V_{DD} to the data retention (V_{CCDR} , 2.0 V) voltage.



AC Switching Characteristics

Over the Operating Range

Parameter [8]	Description	-1	0	Unit
Parameter ¹⁰¹	Description	Min	Max	Unit
Read Cycle				
t _{power}	V _{CC} (typical) to the first access ^[9]	1	Ι	ms
t _{RC}	Read Cycle Time	10	-	ns
t _{AA}	Address to Data Valid	-	10	ns
t _{OHA}	Data Hold from Address Change	3	-	ns
t _{ACE}	CE ₁ LOW/CE ₂ HIGH to Data Valid	-	10	ns
t _{DOE}	OE LOW to Data Valid	-	5	ns
t _{LZOE}	OE LOW to Low Z	1	-	ns
t _{HZOE}	OE HIGH to High Z ^[10]	-	5	ns
t _{LZCE}	CE ₁ LOW/CE ₂ HIGH to Low Z ^[10]	3	-	ns
t _{HZCE}	CE ₁ HIGH/CE ₂ LOW to High Z ^[10]	_	5	ns
t _{PU}	CE ₁ LOW/CE ₂ HIGH to Power Up ^[11]	0	-	ns
t _{PD}	CE ₁ HIGH/CE ₂ LOW to Power Down ^[11]	_	10	ns
t _{DBE}	Byte Enable to Data Valid	_	5	ns
t _{LZBE}	Byte Enable to Low Z	1	-	ns
t _{HZBE}	Byte Disable to High Z	_	5	ns
Write Cycle [12,	, 13]			
t _{WC}	Write Cycle Time	10	_	ns
t _{SCE}	CE ₁ LOW/CE ₂ HIGH to Write End	7	-	ns
t _{AW}	Address Setup to Write End	7	-	ns
t _{HA}	Address Hold from Write End	0	-	ns
t _{SA}	Address Setup to Write Start	0	-	ns
t _{PWE}	WE Pulse Width	7	-	ns
t _{SD}	Data Setup to Write End	5.5	-	ns
t _{HD}	Data Hold from Write End	0	-	ns
t _{LZWE}	WE HIGH to Low Z ^[10]	3	-	ns
t _{HZWE}	WE LOW to High Z ^[10]	-	5	ns
t _{BW}	Byte Enable to End of Write	7	-	ns

Notes

This part has a voltage regulator that steps down the voltage from 3 V to 2 V internally. t_{power} time must be provided initially before a Read/Write operation is started.
 t_{HZOE}, t_{HZCE}, t_{HZVE}, t_{HZDE} and t_{LZOE}, t_{LZCE}, t_{LZWE}, t_{LZBE} are specified with a load capacitance of 5 pF as in (b) of Figure 3 on page 6. Transition is measured ±200 mV from steady-state voltage.

11. These parameters are guaranteed by design and are not tested.

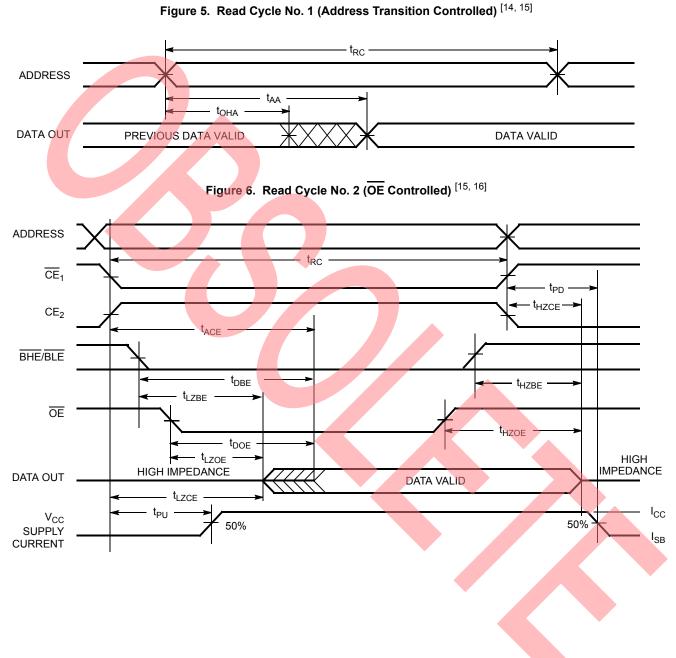
13. The minimum Write cycle time for Write Cycle No. 2 (WE controlled, OE LOW) should be equal to the sum of tsD and tHZWE.

^{8.} Test conditions assume signal transition time of 3 ns or less, timing reference levels of 1.5 V, input pulse levels of 0 to 3.0 V, and output loading of the specified I_{OL}/I_{OH} and specified transmission line loads. Test conditions for the Read cycle use output loading shown in (a) of the Figure 3 on page 6, unless specified otherwise.

^{12.} The internal Write time of the memory is defined by the overlap of \overline{CE}_1 LOW (CE₂ HIGH) and \overline{WE} LOW. Chip enables must be active and \overline{WE} and byte enables must be LOW to initiate a Write, and the transition of any of these signals can terminate the Write. The input data setup and hold timing should be referenced to the leading edge of the signal that terminates the Write.



Switching Waveforms

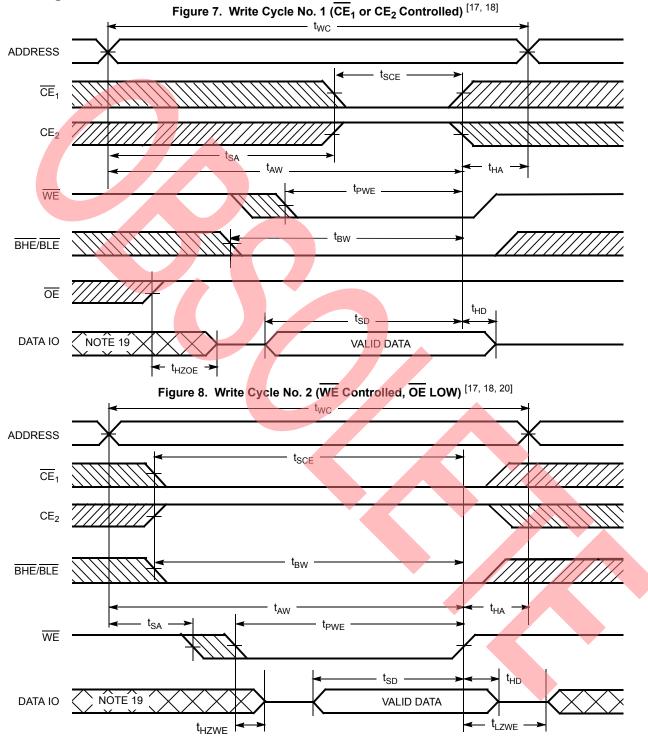


Notes

14. Device is continuously selected. \overline{OE} , \overline{CE} , \overline{BHE} or \overline{BHE} , or both = V_{IL} . $CE_2 = V_{IH}$. 15. WE is HIGH for Read cycle. 16. Address valid prior to or coincident with \overline{CE}_1 transition LOW and CE_2 transition HIGH.



Switching Waveforms (continued)

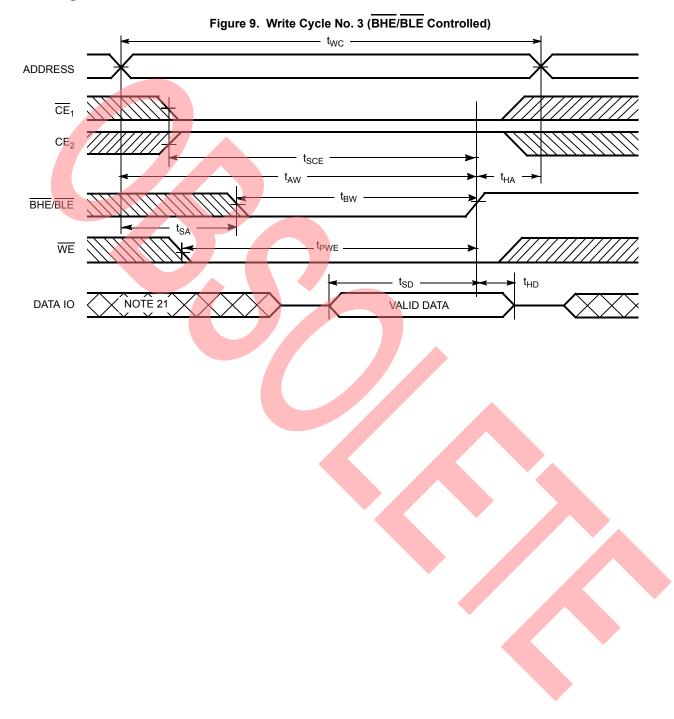


Notes

- 17. Data IO is high impedance if \overline{OE} , or \overline{BHE} or \overline{BLE} or both = V_{IH}. 18. If \overline{CE}_1 goes HIGH simultaneously with WE going HIGH, the output remains in a high impedance state. 19. During this period, the IOs are in output state and input signals should not be applied.
- 20. The minimum write cycle pulse width should be equal to the sum of tSD and tHZWE.



Switching Waveforms (continued)







Truth Table

CE ₁	CE ₂	OE	WE	BLE	BHE	I/O ₀ –I/O ₇	I/O ₈ –I/O ₁₅	Mode	Power
Н	Х	Х	Х	Х	Х	High Z	High Z	Power Down	Standby (I _{SB})
Х	L	Х	X	X	Х	High Z	High Z	Power Down	Standby (I _{SB})
L	Н	L	Н	L,	L	Data Out	Data Out	Read All Bits	Active (I _{CC})
L	Н	L	Н	L	Н	Data Out	High Z	Read Lower Bits Only	Active (I _{CC})
L	н	L	Н	н	L	High Z	Data Out	Read Upper Bits Only	Active (I _{CC})
L	н	Х	L	L	L	Data In	Data In	Write All Bits	Active (I _{CC})
L	Н	Х	L	L	Н	Data In	High Z	Write Lower Bits Only	Active (I _{CC})
L	H	Х	L	Н	L	High Z	Data In	Write Upper Bits Only	Active (I _{CC})
L	Н	Н	Н	Х	X	High Z	High Z	Selected, Outputs Disabled	Active (I _{CC})

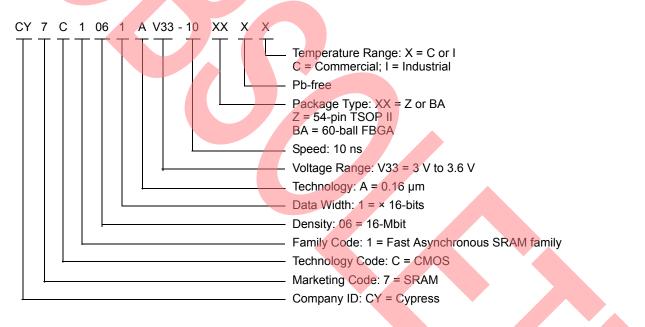


Ordering Information

The following table lists the CY7C1061AV33 key package features and ordering codes. The table contains only the parts that are currently available. If you do not see what you are looking for, contact your local sales representative. For more information, visit the Cypress website at www.cypress.com and refer to the product summary page at http://www.cypress.com/products.

Speed (ns)	Ordering Code	Package Diagram	Package Type	Operating Range
10	CY7C1061AV33-10ZXC	51-85160	54-pin TSOP II (Pb-free)	Commercial
	CY7C1061AV33-10ZXI	51-85160	54-pin TSOP II (Pb-free)	Industrial
	CY7C1061AV33-10BAXI	<u>51-85162</u>	60-ball FBGA (Pb-free)	

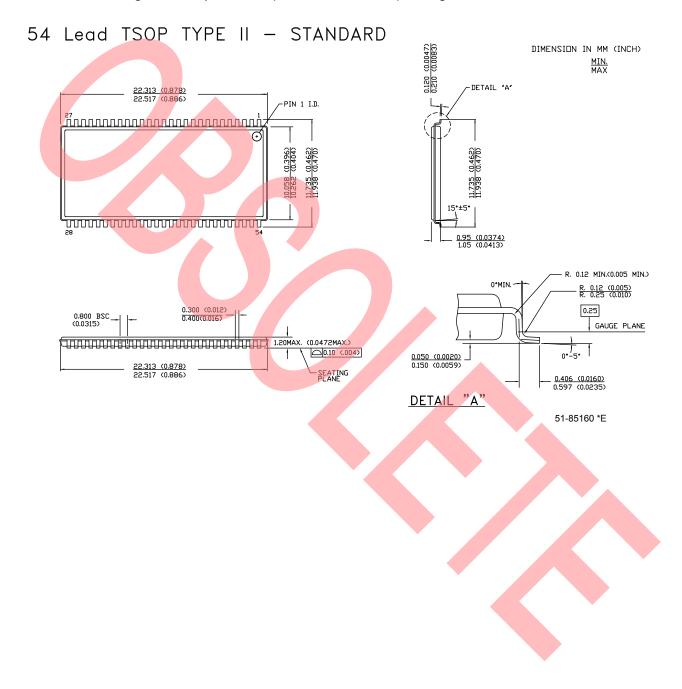
Ordering Code Definitions





Package Diagrams

Figure 10. 54-pin TSOP II (22.4 × 11.84 × 1.0 mm) Package Outline, 51-85160





Package Diagrams (continued)

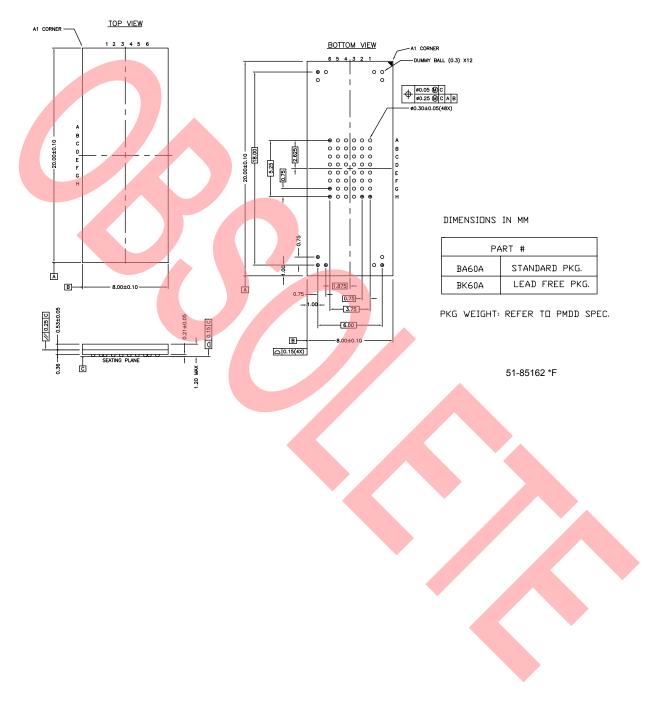


Figure 11. 60-ball FBGA (8 × 20 × 1.2 mm) Package Outline, 51-85162



Acronyms

Acronym	Description		
CMOS	Complementary Metal Oxide Semiconductor		
FBGA	Fine-Pitch Ball Grid Array		
I/O	Input/Output		
OE	Output Enable		
SRAM	Static Random Access Memory		
TSOP	Thin Small-Outline Package		
TTL	Transistor-Transistor Logic		
WE	Write Enable		

Document Conventions

Units of Measure

Symbol	Unit of Measure			
°C	degree Celsius			
MHz	megahertz			
μA	microampere			
mA	milliampere			
mm	millimeter			
ms	millisecond			
mW	milliwatt			
ns	nanosecond			
Ω	ohm			
%	percent			
pF	picofarad			
V	volt			
W	watt			



Document History Page

Document Title: CY7C1061AV33, 16-Mbit (1M × 16) Static RAM Document Number: 38-05256						
Revision	ECN	Submission Date	Orig. of Change	Description of Change		
**	113725	03/28/02	NSL	New data sheet		
*A	117058	07/ <mark>31/0</mark> 2	DFP	Removed 15-ns bin		
*В	117989	08/30/02	DFP	Added 8-ns bin Changed Icc for 8, 10, 12 bins t_{power} changed from 1 μ s to 1 ms. Load Cap Comment changed (for Tx line load) t_{SD} changed to 5.5 ns for the 10-ns bin Changed some 8-ns bin numbers (t_{HZ} , t_{DOE} , t_{DBE}) Removed hz <lz comments="" data="" from="" sheet<="" td=""></lz>		
*C	120383	11/06/02	DFP	Final data sheet Added note 3 to "AC Test Loads and Waveforms" and note 7 to t _{pu} and t _{pd} Updated Input/Output Caps (for 48BGA only) to 8 pF/10 pF and for the 54-pin TSOP to 6/8 pF		
*D	124439	2/25/03	MEG	Changed ISB1 from 100 mA to 70 mA Shaded fBGA production ordering information		
*E	492137	See ECN	NXR	Corrected Block Diagram on page #1 Removed 8 ns speed bin Changed 48-Ball FBGA to 60-Ball FBGA in Pin Configuration Included Note #1 and 2 on page #2 Changed the description of I _{IX} from Input Load Current to Input Leakage Cur- rent in DC Electrical Characteristics table Updated the Ordering Information Table		
*F	508117	See ECN	NXR	Updated FBGA Pin Configuration Updated Ordering Information table		
*G	877322	See ECN	VKN	Updated Ordering Information table		
*H	2897049	03/22/10	KAO	Removed inactive parts from the ordering information table. Updated package diagrams. Updated links in Sales, Solutions and Legal Information.		
*	3109147	12/13/2010	KAO	Added Ordering Code Definitions under Ordering Information.		
*J	3160428	02/02/11	PRAS	Updated Ordering Information: Updated part numbers. Updated to new template.		
*K	3222127	04/11/2011	PRAS	Added Acronyms and Units of Measure.		
*L	4363272	04/28/2014	MEMJ	Updated Switching Waveforms: Added Note 20 and referred in Figure 8. Updated Package Diagrams: spec 51-85160 – Changed revision from *A to *D. spec 51-85162 – Changed revision from *E to *F. Updated to new template. Completing Sunset Review.		
*M	4578447	01/16/2015	MEMJ	Updated Functional Description: Added "For a complete list of related documentation, click here." at the end. Updated Package Diagrams: spec 51-85160 – Changed revision from *D to *E.		
*N	5738556	05/16/2017	VINI	Obsolete document. Completing Sunset Review.		



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